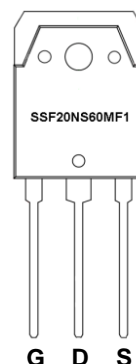
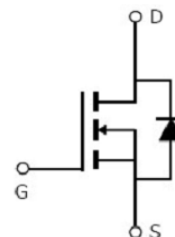


**Main Product Characteristics:**

$V_{DSS}$	600V
$R_{DS(on)}$	0.14 $\Omega$ (typ.)
$I_D$	20A ①


**TO-3P**

**Marking and Pin Assignment**

**Schematic Diagram**
**Features and Benefits:**

- High dv/dt and avalanche capabilities
- 100% avalanche tested
- Low input capacitance and gate charge
- Low gate input resistance


**Description:**

The SSF20NS60MF1 series MOSFETs is a new technology, which combines an innovative technology and advance process. This new technology achieves low Rdson, energy saving, high reliability and uniformity, superior power density and space saving.

**Absolute Max Rating:**

Symbol	Parameter	Max.	Units
$I_D$ @ TC = 25°C	Continuous Drain Current, $V_{GS}$ @ 10V ①	20	A
$I_{DM}$	Pulsed Drain Current ②	60	
$P_D$ @TC = 25°C	Power Dissipation ③	151	W
$V_{DS}$	Drain-Source Voltage	600	V
$V_{GS}$	Gate-to-Source Voltage	$\pm 30$	V
$E_{AS}$	Single Pulse Avalanche Energy	3.4	mJ
$I_{AR}$	Avalanche Current	418	A
$T_J$ $T_{STG}$	Operating Junction and Storage Temperature Range	-55 to +150	°C

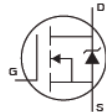
## Thermal Resistance

Symbol	Characteristics	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-case ③	—	0.83	$^{\circ}\text{C}/\text{W}$
$R_{\theta JA}$	Junction-to-ambient ( $t \leq 10\text{s}$ ) ④	—	62	$^{\circ}\text{C}/\text{W}$

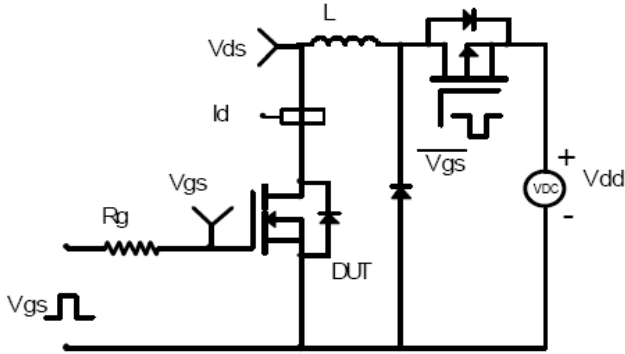
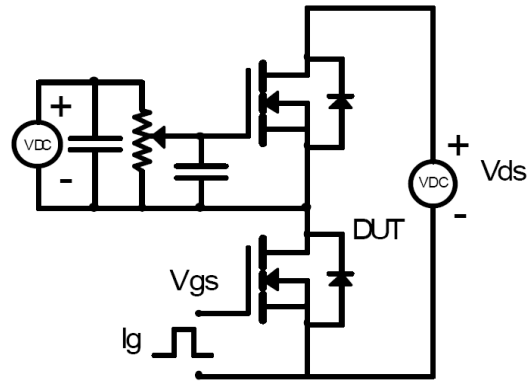
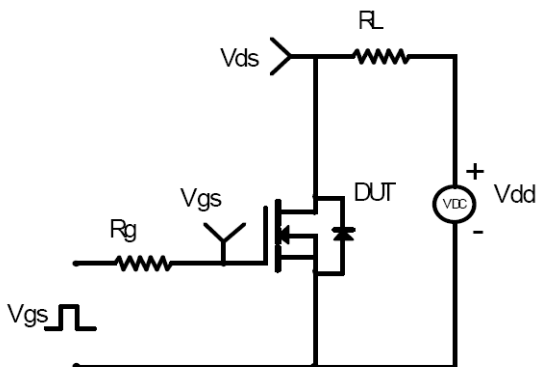
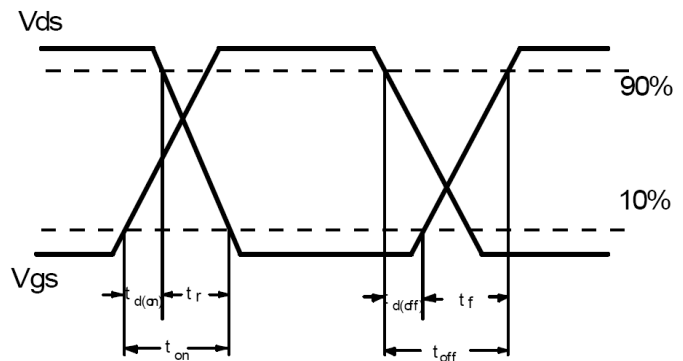
## Electrical Characteristics @ $T_A=25^{\circ}\text{C}$ unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source breakdown voltage	600	—	—	V	$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$
$R_{DS(on)}$	Static Drain-to-Source on-resistance	—	0.14	0.16	$\Omega$	$V_{GS}=10\text{V}, I_D=10\text{A}$
$V_{GS(th)}$	Gate threshold voltage	2.5	—	4	V	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$
$I_{DSS}$	Drain-to-Source leakage current	—	—	1	$\mu\text{A}$	$V_{DS} = 600\text{V}, V_{GS} = 0\text{V}$
$I_{GSS}$	Gate-to-Source forward leakage	—	—	100	nA	$V_{GS} = 30\text{V}$
		—	—	-100		$V_{GS} = -30\text{V}$
$Q_g$	Total gate charge	—	38	—	nC	$I_D = 20\text{A},$ $V_{DS}=480\text{V},$ $V_{GS} = 10\text{V}$
$Q_{gs}$	Gate-to-Source charge	—	8	—		
$Q_{gd}$	Gate-to-Drain("Miller") charge	—	14.5	—		
$t_{d(on)}$	Turn-on delay time	—	31	—	ns	$V_{GS}=10\text{V}, V_{DS} = 400\text{V},$ $R_{GEN}=25\Omega, I_D = 20\text{A}$
$t_r$	Rise time	—	69	—		
$t_{d(off)}$	Turn-Off delay time	—	124	—		
$t_f$	Fall time	—	48	—		
$C_{iss}$	Input capacitance	—	1726	—	pF	$V_{GS} = 0\text{V}$ $V_{DS} = 100\text{V}$ $f = 1\text{MHz}$
$C_{oss}$	Output capacitance	—	71	—		
$C_{riss}$	Reverse transfer capacitance	—	5	—		

## Source-Drain Ratings and Characteristics

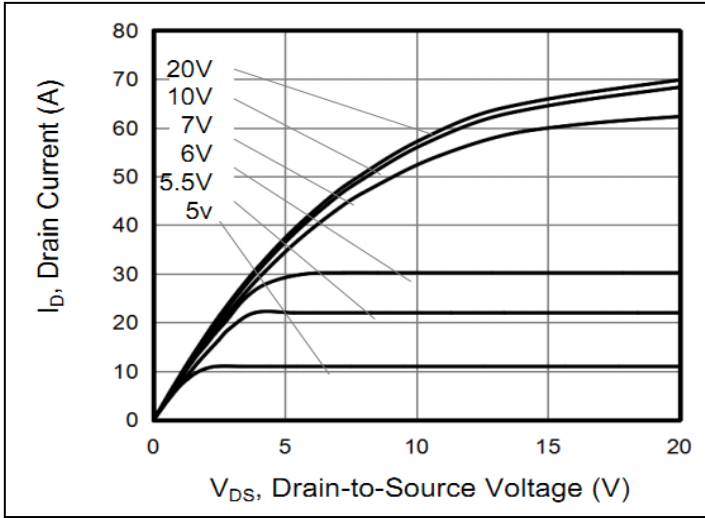
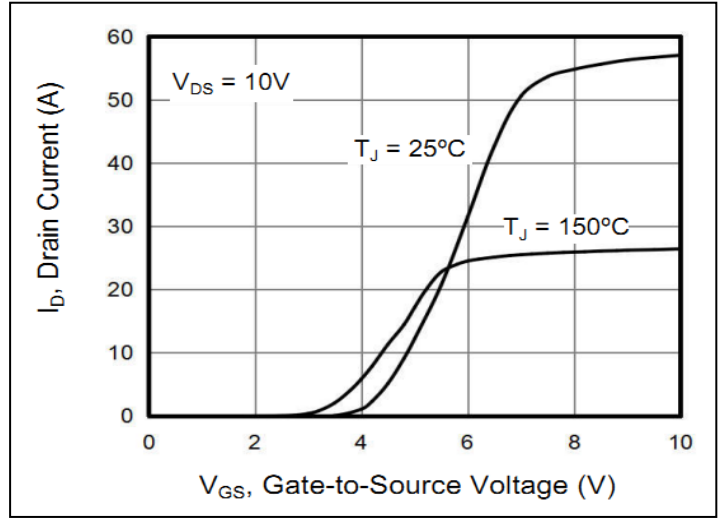
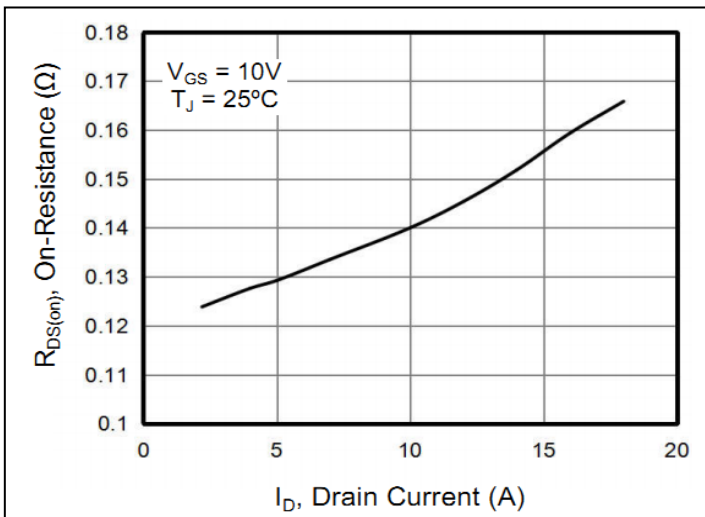
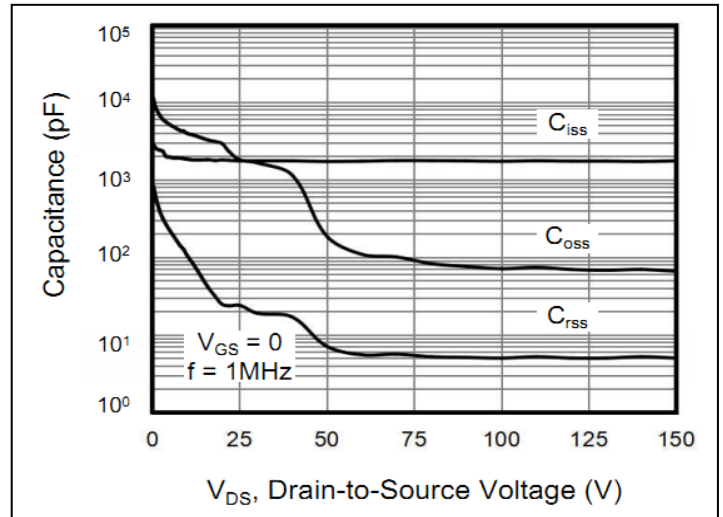
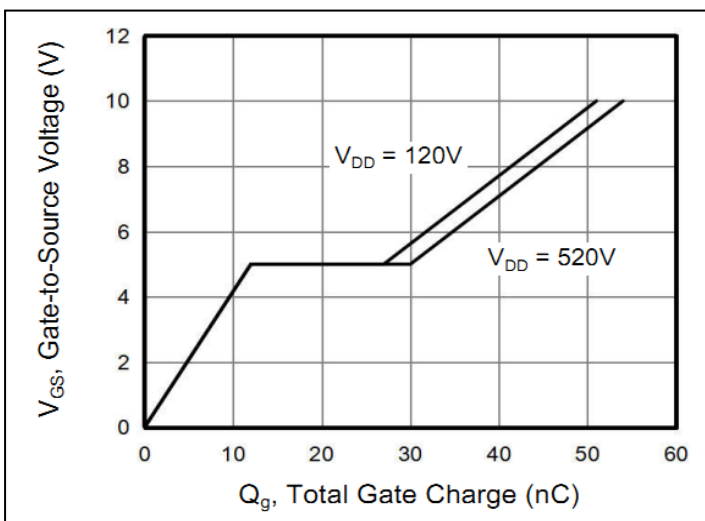
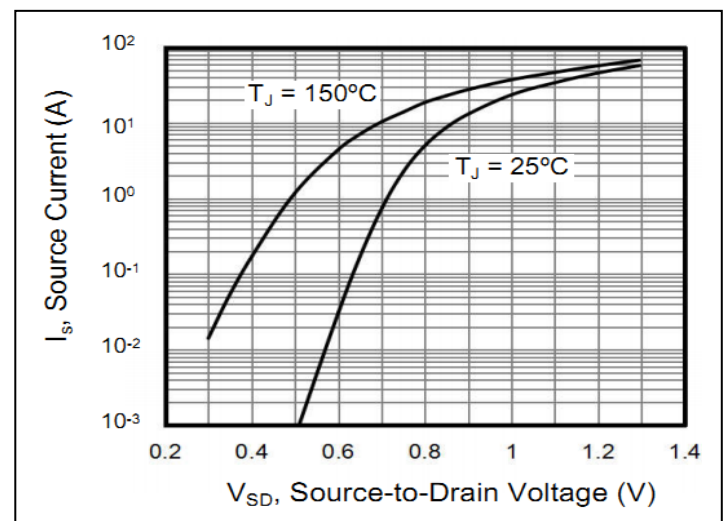
Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$I_S$	Continuous Source Current (Body Diode) ①	—	—	20	A	MOSFET symbol showing the integral reverse p-n junction diode. 
$I_{SM}$	Pulsed Source Current (Body Diode)	—	—	60	A	
$V_{SD}$	Diode Forward Voltage	—	0.9	1.2	V	$I_S=20\text{A}, V_{GS}=0\text{V}$
$t_{rr}$	Reverse Recovery Time	—	460	—	ns	$T_J = 25^{\circ}\text{C}, I_F = 20\text{A},$
$Q_{rr}$	Reverse Recovery Charge	—	5500	—	nc	$di/dt = 100\text{A}/\mu\text{s}$

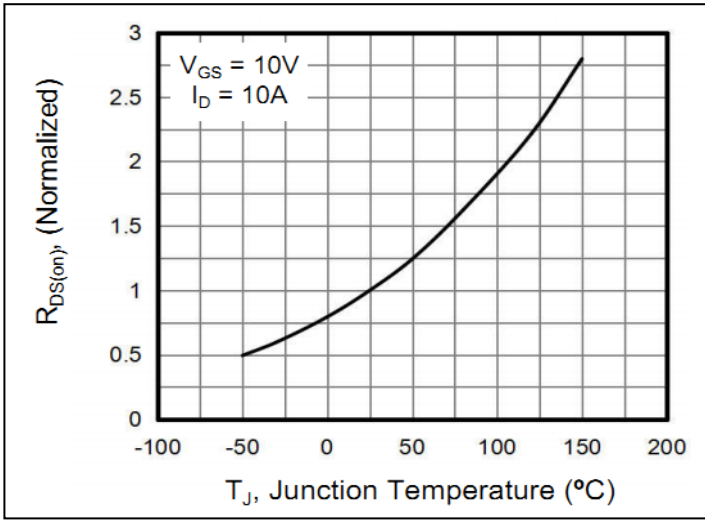
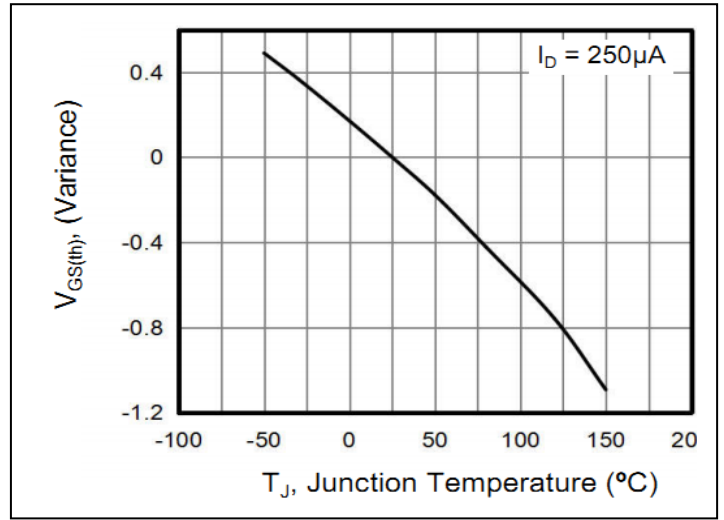
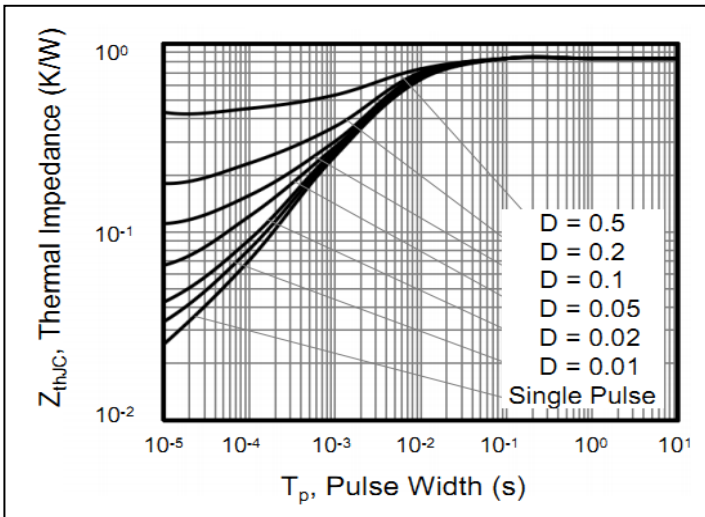
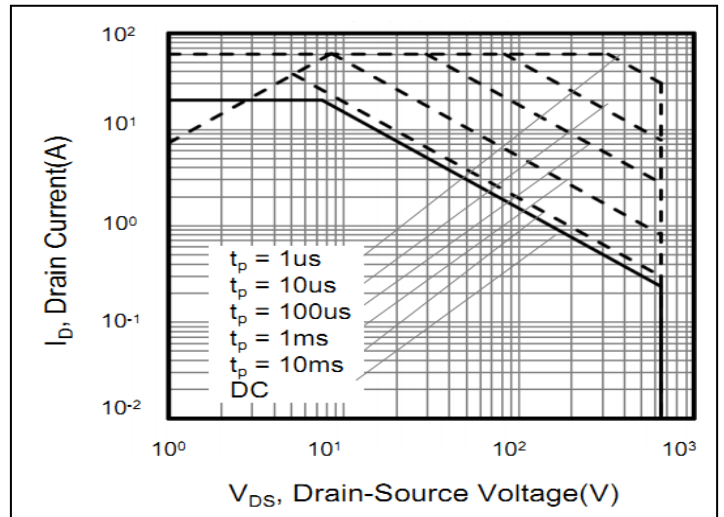
## Test circuits and Waveforms

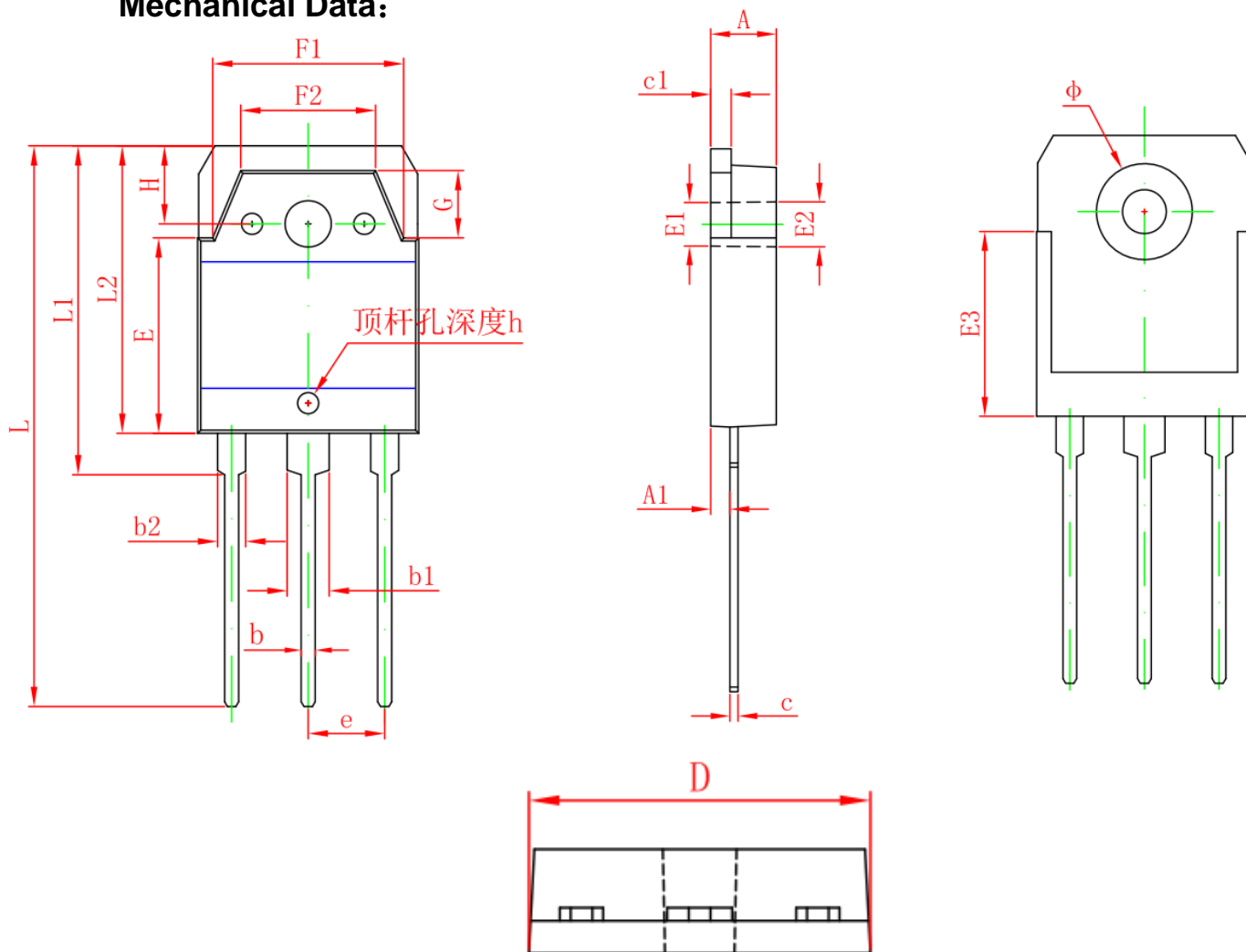
**EAS Test Circuit:**

**Gate charge test circuit:**

**Switching Time Test Circuit:**

**Switching Waveforms:**


### Notes:

- ① Calculated continuous current based on maximum allowable junction temperature.
- ② Repetitive rating; pulse width limited by max. junction temperature.
- ③ The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.
- ④ The value of  $R_{\theta JA}$  is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with  $T_A = 25^\circ\text{C}$

**Typical electrical and thermal characteristics**

**Figure 1: Typical Output Characteristics**

**Figure 2: Transfer Characteristics**

**Figure 3: On-Resistance vs. Drain Current**

**Figure 4: Capacitance**

**Figure 5: Gate Charge**

**Figure 6: Body Diode Forward Voltage**

**Typical electrical and thermal characteristics**

**Figure 7: On-Resistance vs. Junction Temperature**

**Figure 8: Threshold Voltage vs. Junction Temperature**

**Figure 9: Transient Thermal Impedance**

**Figure 10: Safe Operation Area**

**Mechanical Data:**


Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min	Max	Min	Max
A	4.600	5.000	0.181	0.197
A1	1.200	1.600	0.047	0.063
b	0.800	1.200	0.031	0.047
b1	2.800	3.200	0.110	0.126
b2	1.800	2.200	0.071	0.087
c	0.500	0.700	0.020	0.028
c1	1.450	1.650	0.057	0.065
D	15.450	15.850	0.608	0.624
E	13.700	14.100	0.539	0.555
E1	3.200 REF		0.126 REF	
E2	3.300 REF		0.130 REF	
E3	13.450 REF		0.530 REF	
F1	13.400	13.800	0.528	0.543
F2	9.400	9.800	0.370	0.386
L	39.900	40.300	1.571	1.587
L1	23.200	23.600	0.913	0.929
L2	20.300	20.600	0.799	0.811
Φ	6.900	7.100	0.272	0.280
G	5.150	5.550	0.203	0.219
e	5.450 TYP		0.215 TYP	
H	5.000 REF		0.197 REF	
h	0.000	0.300	0.000	0.012

**Ordering and Marking Information**
**Device Marking: SSF20NS60MF1**
**Package (Available)**
**TO-3P**
**Operating Temperature Range**
**C : -55 to 150 °C**
**Reliability Test Program**

<b>Test Item</b>	<b>Conditions</b>	<b>Duration</b>	<b>Sample Size</b>
<b>High Temperature Reverse Bias(HTRB)</b>	<b>T<sub>j</sub>=150°C @ 80% of Max V<sub>DSS</sub>/V<sub>CES</sub>/VR</b>	<b>168 hours 500 hours 1000 hours</b>	<b>3 lots x 77 devices</b>
<b>High Temperature Gate Bias(HTGB)</b>	<b>T<sub>j</sub>=150°C @ 100% of Max V<sub>GSS</sub></b>	<b>168 hours 500 hours 1000 hours</b>	<b>3 lots x 77 devices</b>

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**Suzhou Silikron Semiconductor Corp.**

501 , NW-20,Nanopolis, 99th Jinjihu Avenue ,Industrial Park ,Suzhou ,P.R, CHINA

**TEL:** (86-512) 62560688

**FAX:** (86-512) 62560688-8092

**E-mail:** Sales@silikron.com